# TUNICS T100S – Tunable Laser Source High Power with Ultra-Low SSE

**YENISTA** presents a general-purpose benchtop "work-horse" tunable laser, combining large wavelength range and high output power with SSE suppression. This laser is a must for all optical labs looking for an affordable every day use laser. With TUNICS T100S, the laser is not anymore the limiting factor of your measurement set-up.

### **Key Parameters**

### High <u>and</u> SSE-free Output Power: a unique combination ideal for Component Testing

With T100 technology, there is no more trade-off between high output power and SSE suppression. A single laser can be used for all applications from amplifiers/WDM testing to high resolution insertion loss characterization.

### ■ 110 / 150 nm Tuning Range with 1 pm Resolution

In one single instrument, the TUNICS guarantees a tuning range of up to 150 nm at 0 dBm (1 mW).

### Fast Operation from the Start

The TUNICS laser can be used a minute after turn-up. Scanning time between two wavelengths is around 1 second and sweeping speed is adjustable from 1 nm/s to up to 100 nm/s.

### Active Control for Mode-Hop-Free Operation

For ultimate performance, TUNICS T100S features a proprietary active control that ensures perfect mode-hop-free operation and accurate wavelength sweep over its entire tuning range.

## ■ Fine Scanning Mode: down to 0.1 pm resolution and frequency modulation

Fine Scanning Mode allows the user to accurately modify the wavelength over ±2 GHz range using the rotary knob on instrument front panel. An external modulation could also be applied to modulate this fine scanning.

### Step-by-Step and Sweeping Mode

The TUNICS T100S combines two operating modes. The sweeping ability delivers a continuous variation of the wavelength at a constant rate to enable a fast and uninterrupted measurement. In step-by-step application, the laser exhibits a high wavelength stability suitable for long-term testing.

### Internal wavelength reference

Every TUNICS T100S has an internal wavelength reference that leads to a  $\pm 30$  pm absolute wavelength accuracy. This eliminates the need for an external wavemeter or optical spectrum analyzer.



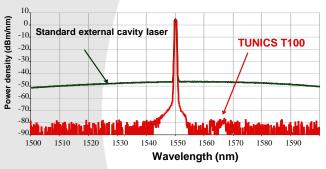


Fig.1 TUNICS T100S SSE-free Optical Spectrum

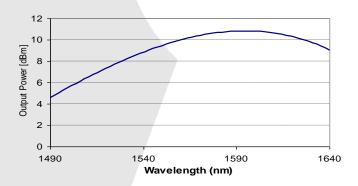


Fig. 2 Typical power vs. wavelength (CL-WB Model)

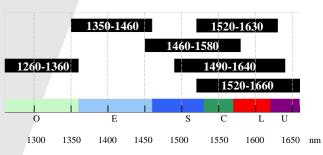


Fig. 3 AvailableT100S Models



### **TUNICS T100S Specifications**

	T100S-O	T10	00S-E	T100S-SC	T100S-CL	T100S-CL-WB	T100S-CLU
Wavelength range							
• P = 0 dBm	1260-1360 nm	1350-	1460 nm	1460-1580 nm	1520-1630 nm	1490-1640 nm	1520-1660 nm
• P = 6 dBm	1290-1340 nm	1360-	1430 nm	1480-1570 nm	1540-1620 nm	1520-1630 nm	1540-1620 nm
• P = 8 dBm					1560-1600 nm	1540-1610 nm	1560-1600 nm
TUNING CHARACTERISTICS							
Absolute wavelength accuracy *1				±30	pm		
Wavelength stability *2	±5 pm / h (±3 pm / h typical and ±5 pm					ypical)	
Tuning repeatability (typ.)				5 pm			
Wavelength setting resolution				1 pm			
Optical frequency fine tuning				±2 GHz			
Tuning speed (typ.)				1s (100 nm)			
LASER OUTPUT CHARACTERISTICS							
Power stability *2				±0.01 dB / h (±0.02	5 dB / 24h typical)		
Side mode suppression ratio *3	>40 dB					>45 dB	
Signal to source spontaneous-emission ratio *4	>80 dB				>90 dB		
Relative intensity noise *3, *5		- 145 dB/Hz (typ.)					
Spectral width (FWHM)	400 kHz typical (coherence control OFF) >100 MHz (coherence control ON)						
SWEEPING MODE CHARACTERISTICS							
Mode hop free range	Full s			specified wavelength and power ranges *8			
Scan speed				Adjustable from 1 to 100 nm/s			
Power flatness during scan (typ.)	±0.25 dB						
Power repeatability from scan to scan (typ.) *6	±0.05 dB						
Interfaces							
Optical connector	FC-APC						
Output fiber	SMF-28™ (PMF option available)						
Output isolation	35 dB						
Return loss	60 dB						
Remote control	RS-232 C and IEEE-488.1*7						
Low frequency modulation	10 kHz to 8 MHz						
High frequency modulation	30 kHz to 200 MHz						
ENVIRONMENT							
Operating temperature range	+15° to +30°C +60° to +85°F						
Power supply	100 to 240 V / 50 to 60 Hz						
Dimensions(W x H x D) in mm <sup>3</sup>	448 x 133 x 370						
Weight	12.5 kg						

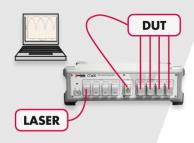
Unless otherwise specified, specifications are given after 30 minutes warm-up. \*1: After self calibration, at +20°C. Over operating temperature range wavelength accuracy is ±40pm for O, E, SC, CL and CL-WB models.

- \*2: Over one hour at a constant temperature and after 1 hour warm-up.
- \*3: Measured with 0 dBm output power.

- \*4: Spontaneous emission measured on a 0.1 nm bandwidth at  $\pm 1 \text{ nm}$  from the signal.
- \*5: Measured at an electrical frequency of 100 MHz.
- \*6: Over 100 scans at constant temperature.
- \*7: Tested and validated with National Instruments GPIB board.
- \*8: 1270-1340 nm at 0 dBm for O band model.

### **TUNICS T100S and CT400 Component Tester: the perfect match**

When used in conjunction with Yenista's CT400 component tester, the TUNICS T100S allows accurate insertion characterization in real time. Refer to CT400 individual data sheet for more details.



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